DERIVATOGRAPHIC STUDY OF THE THERMAL BEHAVIOUR OF 13 RARE EARTH ELEMENT OXIDES

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Abstract

The simultaneous TG-DTG-DTA thermoanalytical curves of 13 rare earth (4f) element oxides, namely, CeO₂, Dy₂O₃, Er₂O₃, Gd₂O₃, HfO₂, Ho₂O₃, Nd₂O₃, Pr₆O₁₁, Sm₂O₃, Tb₄O₇, Tm₂O₃, Yb₂O₃ and Y₂O₃, were recorded with a MOM derivatograph under static air atmosphere over the temperature range from ambient to 1050°C. Only HfO₂, Nd₂O₃, Pr₆O₁₁, Sm₂O₃ and Tb₄O₇ showed appreciable weight losses due to the liberation of small amounts of oxygen. X-ray diffractometry was used to identify the thermal degradation products and their precursors.

Keywords: rare earth element oxides, TG-DTG-DTA, XRD

Introduction

At certain temperatures and pressures, the rare earth element (REE) oxides act as positive-type or negative-type semiconductors, catalysing the degradation of inorganic [1] and organic [2] compounds, i.e. decreasing or increasing their thermal stability through a mechanism of formation of unstable intermediates with the host species. Of course, this behaviour is a function of the nonstoichiometry or defect state of the oxide, or in other words the difference in movement of (+) holes and (-) electrons. Some investigators have found [3-4] that for REE oxides to behave as positive- or negative-type semiconductors there should be a certain REE/O₂ ratio, since the latter determines the nature of the defective structure of the oxide.

As far as the author is aware, no systematic derivatographic study of REE oxides has been carried out. This paper describes such a study, the aim of which was to shed light on their thermal stability and catalytic behaviour.

Experimental

All chemicals were analytical grade reagents (puriss) with a purity of not less than 99.99%, obtained from Fluka AG (Buchs). A MOM derivatograph

was used to produce the thermoanalytical curves of the 13 REE oxides (Table 1). For the sake of brevity, thermograms for the thermally stable oxides are not shown since they contain no phase transformation details.

Parameters	Settings
Sample weight	100 mg (ground to 200-300 mesh)
Reference materials	α -Al ₂ O ₃
Crucibles	Platinum, MOM No. 3
Atmosphere	Static air
Heating rate	10 deg·min ⁻¹
Heating program	Ambient-1050°C
Starting voltage	87 volts
Sensitivities:	
TG	100 mg
DTG	1/5
DTA	1/5

Table 1 Optimised instrumental parameters for REE oxides

Results and discussion

A careful scrutiny of the thermograms recorded for CeO₂, Dy_2O_3 , Er_2O_3 , Gd_2O_3 , Ho_2O_3 , Tm_2O_3 , Yb_2O_3 and Y_2O_3 demonstrated their complete thermal stability, without any phase transformation.

Figure 1 depicts the thermoanalytical curves of (a) Pr_6O_{11} and (b) HfO₂. The latter is seen to be thermally stable up to 600°C. Thereafter, a gradual loss in weight is observed in the TG curve. At the end of the heating program (1050°C), this reaches 8 wt%, which is equivalent to the escape of one oxygen atom per mole of HfO₂,

 $HfO_2 \xrightarrow{\Delta} HfO + 1/2O_2$

The XRD patterns [5] for samples heated up to 1000° C and then cooled prove the presence of HfO₂ alone. This means that beyond 600°C the divalent state, HfO is obtained, which is stable only at high temperature; on cooling to ambient conditions, the tetravalent state is restored by combination with atmospheric oxygen (this is shown by the cooling curve, which is not given here for brevity). The TG curve (Fig. 1a) indicates that Pr_6O_{11} [6–8] (a dark-brown powder) undergoes a weight loss of 1.6 wt% between 220 and 310°C. This loss is equivalent to one oxygen atom per mole of Pr_6O_{11} :

$$\Pr_6O_{11} \xrightarrow{\text{heating}} \Pr_6O_{10} + 1/2O_2$$

Beyond 310°C, a meagre degradation continues up to the ceiling temperature of the program. The XRD patterns of the end-products [9] confirm the presence of Pr_6O_{11} . This indicates that, on cooling to room temperature, the unstable intermediate Pr_6O_{10} is reoxidized to Pr_6O_{11} .



Fig. 1 TG, DTG and DTA curves of : (a) Pr₆O₁₁ and (b) HfO₂

This explains why Pr_6O_{11} acts as an *n*-type catalyst semiconductor at high temperature [10].

 Sm_2O_3 undergoes a slight degradation in one step (Fig. 2a), characterized by three endotherms, at 250, 420 and 490°C and two DTG endotherms, at 420 and 490°C, corresponding to the loss of one oxygen atom per mole of oxide:

$$Sm_2O_3 \xrightarrow{\text{heating}} 2SmO + 1/2O_2$$

X-ray analysis reveals the presence of strong lines of Sm_2O_3 in the end-products, but very weak lines of SmO. This proves that the intermediate SmO is stable only at high temperature, and is reoxidized by atmospheric oxygen on returning to room temperature.



Fig. 2 TG, DTG and DTA curves of: (a) Sm₂O₃ (b) Tb₄O₇ and (c) Nd₂O₃ (DTG is not given for brevity)

Figure 2b depicts the results of thermal analysis of Tb₄O₇. The weight losses relating to the tiny step in the TG curve allow determination of the oxygen lost (a total of 3 wt%) at 505° and 890°C. Calculation on the basis of oxygen atoms lost pointed to the formation of Tb₂O₃·TbO_{1.823}. The XRD pattern of a samples sintered at 1000°C indicated the presence of strong *d*-lines of Tb₄O₇, but only very weak *d*-lines relating to Tb₂O₃·TbO_{1.823}. Moreover, the typical dark-brown colour of terbium(III, IV) oxide remained as prior to heating.

In the DTA and TG curves (Fig. 2c) for Nd₂O₃, one endothermic effect and one degradation step ($\Delta T_{min} = 285^{\circ}$ C) were observed; the effect can be assigned to oxygen weight loss. Beyond 320°C, only negligible losses were seen.

It could be concluded that only 5 of the 13 REE oxides investigated show thermal stability at high temperature.

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Zusammenfassung — Mittels eines MOM-Derivatographen wurden in statischer Atmosphäre im Temperaturbereich von Raumtemperatur bis 1050°C die simultanen TG-DTG-DTA thermoanalytischen Kurven von 13 Seltenerdenelementoxiden, namentlich von CeO₂, Dy₂O₃, Er₂O₃, Gd₂O₃, HfO₂, Ho₂O₃, Nd₂O₃, Pr₆O₁₁, Sm₂O₃, Tb₄O₇, Tm₂O₃, Yb₂O₃ und von Y₂O₃ aufgenommen. Lediglich HfO₂, Nd₂O₃, Pr₆O₁₁, Sm₂O₃ und Tb₄O₇ zeigten einen nennenswerten Gewichtsverlust, verursacht durch eine geringe Freisetzung von Sauerstoff. Zur Identifizierung der thermischen Zerfallsprodukte und ihrer Vorstufen wurde die Röntgendiffraktometrie herangezogen.